

**Search Notes**

Application/Control No.

10/025,960

Examiner

Brian E. Miller

Applicant(s)/Patent under  
Reexamination

TANAKA, YOICHIRO

Art Unit

2652

**SEARCHED**

Class	Subclass	Date	Examiner
360	324		
360	324.1		
360	324.12		
360	135	1/20/2005	BEM

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
360	324.12		
360	135	1/20/2005	BEM

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR